

**HAOPIN MICROELECTRONICS CO.,LTD.**
**Description**

Glass passivated, sensitive gate thyristors in a plastic envelope, intended for use in general purpose switching and phase control applications. These devices are intended to be interfaced directly to microcontrollers, logic integrated circuits and other low power gate trigger circuits.

Symbol		Simplified outline
		 TO-252
Pin	Description	
1	Cathode	
2	anode	
3	gate	
TAB	anode	

**Applications:**

- ◆ Motor control
- ◆ Industrial and domestic lighting
- ◆ Heating
- ◆ Static switching

**Features**

- ◆ Blocking voltage to 600 V
- ◆ On-state RMS current to 8 A
- ◆ Ultra low gate trigger current

SYMBOL	PARAMETER	Value	Unit
$V_{DRM}$	Repetitive peak off-state voltages	600	V
$I_T \text{ (RMS)}$	RMS on-state current (full sine wave)	8	A
$I_{TSM}$	Non-repetitive peak on-state current (full cycle, $T_j$ initial=25°C)	83	A

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT
$R_{th j-mb}$	Thermal resistance Junction to mounting base		-	-	2.0	K/W
$R_{th j-a}$	Thermal resistance Junction to ambient	In free air	-	70	-	K/W

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Limiting values in accordance with the Maximum system(IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN	Value	UNIT
$V_{DRM}$	Repetitive peak off-state Voltages		-	600	V
$I_{T(RMS)}$	RMS on-state current	Full sine wave; $T_c \leq 110^\circ\text{C}$	-	8	A
$I_{TSM}$	Non repetitive surge peak on-state current	$F=50\text{Hz}$ $F=60\text{Hz}$	-	83	A
			-	100	A
$I^2t$	$I^2t$ for fusing	$T_p = 10\text{ms}$	-	41	$\text{A}^2\text{s}$
Di/dt			-	100	$\text{A}/\mu\text{s}$
$I_{GM}$	Peak gate current		-	1	A
$I_{DRM}$	$V_{DRM}=V_{RRM}$	$T_c=25^\circ\text{C}$	-	5	$\mu\text{A}$
$I_{RRM}$	$V_{DRM}=V_{RRM}$	$T_c=110^\circ\text{C}$	-	250	$\mu\text{A}$
$P_{G(AV)}$	Average gate power		-	0.1	W
$P_{GM}$			-	1	W
$T_{stg}$	Storage temperature		-40	150	$^\circ\text{C}$
$T_j$	Junction temperature		-40	150	$^\circ\text{C}$

 $T_j=25^\circ\text{C}$  unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT
Static characteristics						
$I_{GT}$	Gate trigger current	$T_a=25^\circ\text{C}, V_D=6\text{V}, I_t=0.1\text{A}$	-	-	200	$\mu\text{A}$
$V_{GT}$	Gate trigger voltage	$T_c=-40^\circ\text{C}$ $T_c=25^\circ\text{C}$ $T_c=110^\circ\text{C}$	-	-	1 0.8 0.25	V
$I_h$	Holding current	$T_j=25^\circ\text{C}, V_D=12\text{V}, R_{GK}=1\text{k}\Omega$	-	-	6	mA
$V_{GRM}$			6	-	-	V
$dV/dt$			-	8	-	$\text{V}/\mu\text{s}$

**Dynamic Characteristics**

$t_{gt}$	Gate controlled turn-on time	$I_{TM}=10\text{A}; V_D=V_{DRM(max)}; I_g=5\text{mA}; Dl_g/dt=0.2\text{A}/\mu\text{s}$	-	4	-	$\mu\text{s}$
$t_q$	Circuit commutated turn-off time	$V_{DM}=67\% V_{DRM(max)}; T_j=150^\circ\text{C}; I_{TM}=12\text{A}$ $V_R=24\text{V}; dl_{TM}/dt=10\text{A}/\mu\text{s}$ $dv_D/dt=2\text{V}/\mu\text{s}; R_{GK}=1\text{k}\Omega$	-	-	50	$\mu\text{s}$

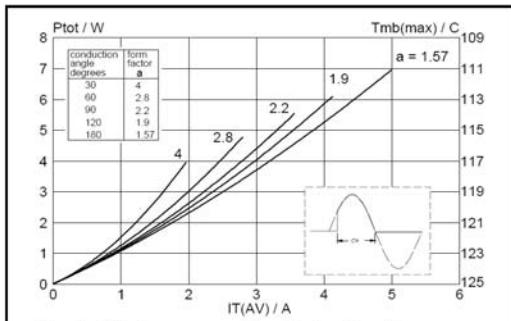
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**Description**


Fig.1. Maximum on-state dissipation,  $P_{tot}$ , versus average on-state current,  $I_T(AV)$ , where  $a = \text{form factor} = I_{T(RMS)} / I_{T(AV)}$

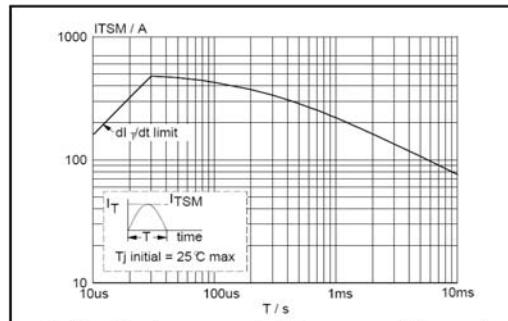


Fig.2. Maximum permissible non-repetitive peak on-state current  $I_{TSM}$ , versus pulse width  $t_p$ , for sinusoidal currents,  $t_p \leq 10\text{ms}$ .

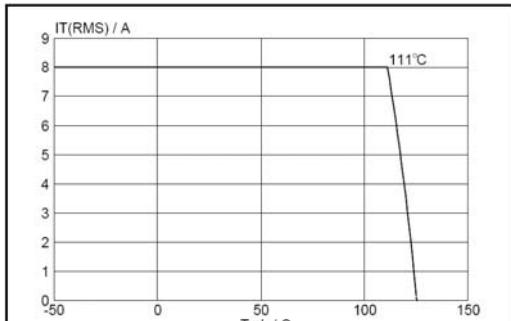


Fig.3. Maximum permissible rms current  $I_{T(RMS)}$ , versus mounting base temperature  $T_{mb}$ .

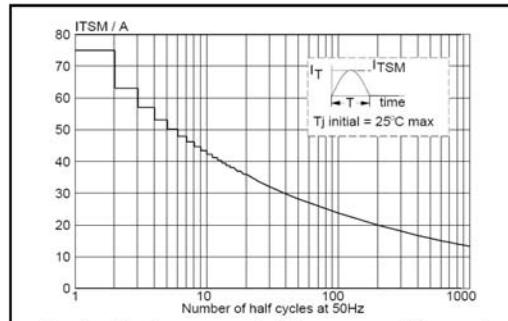


Fig.4. Maximum permissible non-repetitive peak on-state current  $I_{TSM}$ , versus number of cycles, for sinusoidal currents,  $f = 50\text{ Hz}$ .

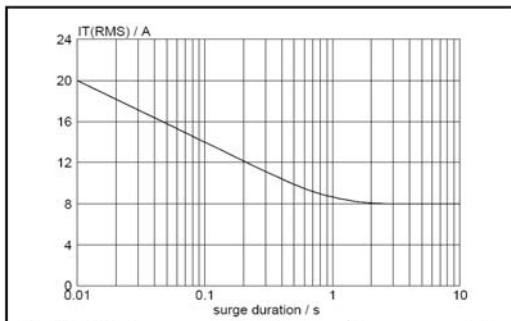


Fig.5. Maximum permissible repetitive rms on-state current  $I_{T(RMS)}$ , versus surge duration, for sinusoidal currents,  $f = 50\text{ Hz}$ ;  $T_{mb} \leq 111^\circ\text{C}$ .

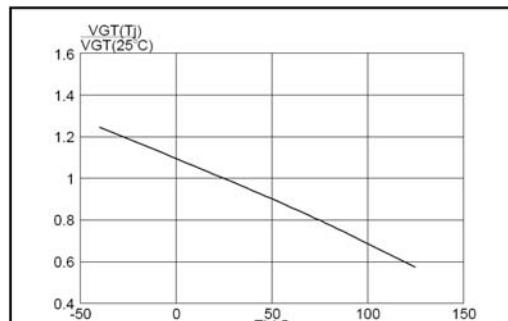


Fig.6. Normalised gate trigger voltage  $V_{GT}(T) / V_{GT}(25^\circ\text{C})$ , versus junction temperature  $T_j$ .

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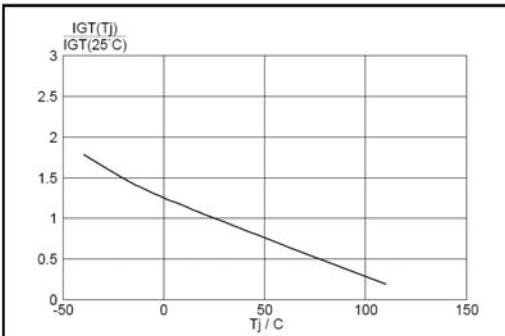


Fig.7. Normalised gate trigger current  $I_{GT}(T_J)/I_{GT}(25^{\circ}C)$ , versus junction temperature  $T_J$ .

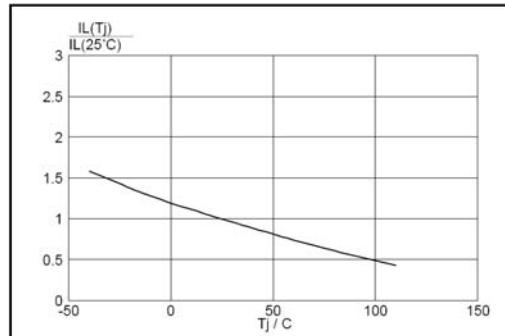


Fig.8. Normalised latching current  $I_L(T_J)/I_L(25^{\circ}C)$ , versus junction temperature  $T_J$ .

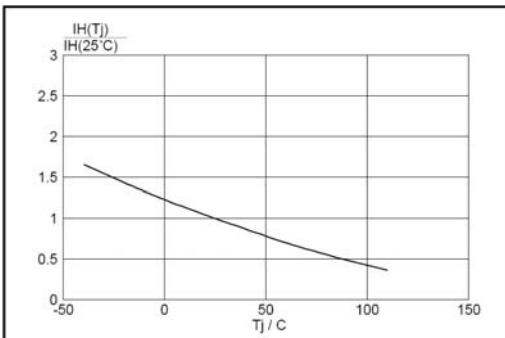


Fig.9. Normalised holding current  $I_H(T_J)/I_H(25^{\circ}C)$ , versus junction temperature  $T_J$ .

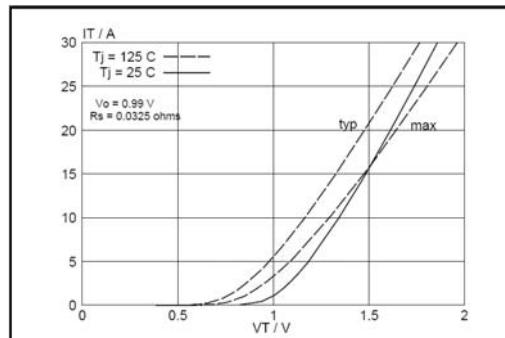


Fig.10. Typical and maximum on-state characteristic.

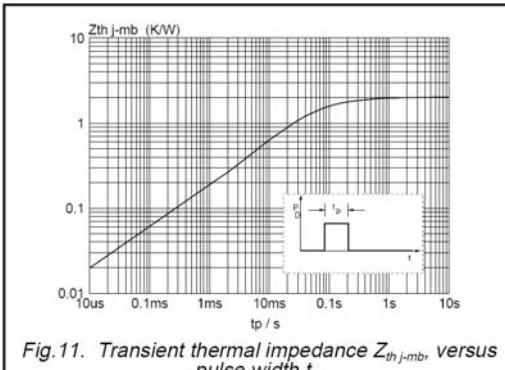


Fig.11. Transient thermal impedance  $Z_{th,j-mb}$ , versus pulse width  $t_p$ .

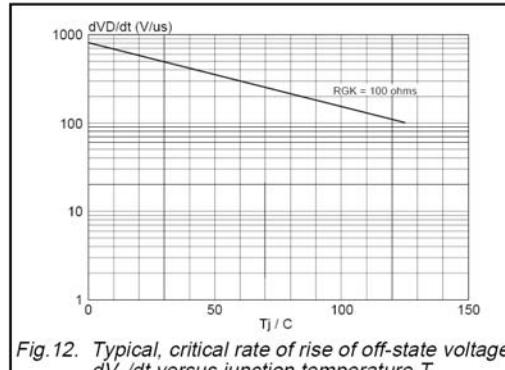


Fig.12. Typical, critical rate of rise of off-state voltage,  $dV_D/dt$  versus junction temperature  $T_J$ .



# S6008DS2

## SCRs

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### MECHANICAL DATA

